



TESTING IC SOCKET

Abstract of the Disclosure:

An IC socket for testing a grid array package, is configured to be fitted with an adapter socket mounted on a test board. The IC socket includes an IC socket body having a bottom plate formed with a number of contact holding holes penetrating through the bottom plate and arranged in the form of a matrix, and a number of contacts each having a contacting end, a spring portion, a fixing base portion and a contacting pin which are arranged in the named order, the fixing base portion of each of the contacts being inserted into a corresponding contact holding hole of the IC socket body from the upperside of the bottom plate. The IC socket also includes a fixing plate having a corresponding number of fixing apertures and fixed on an upper surface of the bottom plate of the IC socket body by passing the contacts through the fixing apertures, respectively, so that the fixing base portion of the contact is fixed between the bottom plate of the IC socket body and an edge portion of the fixing aperture of the fixing plate.

Fig. 5